

Reliability test report

1. Sample information

Name /Model	SMDJ85CA	Quantity	300PCS	Source	RD	Batch/Lot No.	FIN2120035
Background	晟驰微电子-定期可靠性						

2. Application Information

Applicant	XiaoRui Zhang	Department	RD	Date	2022.2.02	Test category	Reliability Test
Test purpose	定期可靠性						

3. Test Method

Reference standard	AEC-Q101/JESD-22 / GJB-128A
Test requirement	According to SPEC

4. Experimental Equipment

No.	Equipment name	Model	ID	Calibration date
1	TVS Semiconductor tester	PTHY2900H	BPMS-3010028-118	2021.03.28~2022.03.27
2	TC Chamber	DNT-1518LA-ZK	BPMS-3010010-089	2021.04.23~2022.04.22
3	PCT Chamber	DL/75L	PMS-3040062-120	2021.06.09~2022.06.08
4	Lead-free solder furnace	ZB1510D	PMS-229	2021.04.03—2022.04.02
5	Lightning generator10/700µs	HGV-II	PMY-3040012-028	2021.04.29~2022.04.28

5. Test Result

No.	Testing items	Testing conditions	Test data	Test results	Remark
	High Temperature Storage Test	Temperature: 150°C 80%VDMAX Time:168h		OK	
6	High Temperature Storage Test	Temperature: 150°C Time:168h		OK	
7	High-low Temperature Cycle test	Temperature: From -55°C to 150°C ,Dwell time : 30min 100cycles		OK	
8	Pressure cooker Test	Temperature: 121°C Humidity:100% 2atm time:96h		OK	
9	UHAST	Temperature: 130°C Humidity:85% 2atm time:96h		OK	
10	Resistance of soldering heat	Temperature: 260±5°C Time : 10s		OK	
11	Surge test	10/1000s :129A±10T		OK	
Unqualified item description					
Conclusion		OK			

Reported by: Chen Gan
Date: 2022. 2. 20

Checked by: TengFei Bi
Date: 2022. 2. 20

Approved by : Yong Liu
Date: 2022. 2. 20